

## PATENT ABSTRACTS OF JAPAN

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(71)Applicant : TOKYO ELECTRON YAMANASHI  
KK

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(72)Inventor : TAKAO ITARU

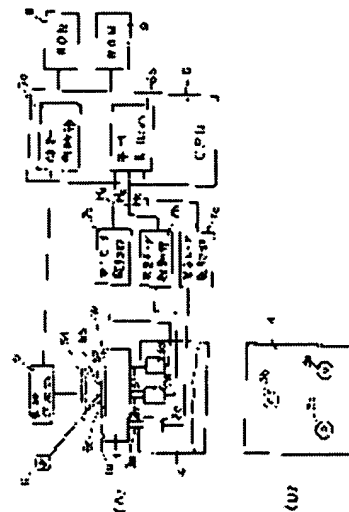
## (54) INSPECTION APPARATUS

## (57)Abstract:

PURPOSE: To impress an accurate test signal by a method wherein the needle point of a probing card is brought into pressure contact with a chip, the degree of an inclination between the needle point of the probing card and the chip is judged on the basis of the size of a formed trace and the needle of the probing card is made parallel with the chip.

CONSTITUTION: A silicon wafer W is placed on a specimen stand 1; the specimen stand 1 is moved to the upper part and overdriven; the needle point of a needle 55 is brought into pressure contact with a pad 52 at a chip 51. Then, large and small traces are formed; they are read out as trace data by means of a trace readout part 5; they are sent to an inclination judgment part 6a.

Then, it is judged on the basis of the trace data that a probing card 54 and the chip 51 are in an inclined state. A parallelism control part 6b performs a computation in order to make the probing card 54 and the chip 51 parallel; parallelism control signals Ha to Hc are sent out to individual servomotors 3a to 3c; the motors are turned in the forward and reverse directions; the specimen stage 1 is inclined and controlled; the probing card 54 and the chip 51 are set to a mutually parallel state.



## LEGAL STATUS

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